

## **IRFPF50PBF-VB Datasheet Power MOSFET**

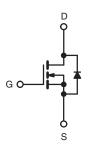
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	950				
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V 2.0				
Q <sub>g</sub> (Max.) (nC)	190				
Q <sub>gs</sub> (nC)	23				
Q <sub>gd</sub> (nC)	110				
Configuration	Single				

### **FEATURES**

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	950	V	
Gate-Source Voltage			$V_{GS}$	± 20	\ \ \ \ \ \	
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$		6.1		
Continuous Drain Current	VGS at 10 V	T <sub>C</sub> = 100 °C	ID	3.9	Α	
Pulsed Drain Current <sup>a</sup>	•		I <sub>DM</sub>	24		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	800	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	6.0	Α	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	19	mJ	
Maximum Power Dissipation $T_C = 25  ^{\circ}C$			P <sub>D</sub>	190	W	
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	1.0	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) for 10 s				300 <sup>d</sup>		
Mounting Tayous		12 oorow		10	lbf ⋅ in	
Mounting Torque	6-32 or M3 screw			1.1	N⋅m	

### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD}=50~V$ , starting  $T_J=25~^{\circ}C$ , L=40~mH,  $R_g=25~\Omega$ ,  $I_{AS}=6.1~A$  (see fig. 12). c.  $I_{SD}\leq 6.1~A$ ,  $dI/dt\leq 120~A/\mu s$ ,  $V_{DD}\leq 600$ ,  $T_J\leq 150~^{\circ}C$ . d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS					
PARAMETER SYMBOL TYP. MAX.					
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	40		
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.65		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0$	V, I <sub>D</sub> = 250 μA	950	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	to 25 °C, I <sub>D</sub> = 1 mA	-	1.2	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V$	<sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>G</sub>	<sub>S</sub> = ± 20 V	-	-	± 100	nA
Zone Onto Waltana Dunin Comment	I <sub>DSS</sub>	V <sub>DS</sub> = 950 V, V <sub>GS</sub> = 0 V		-	-	100	
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 760 V, V	V <sub>DS</sub> = 760 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	500	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 3.6 A <sup>b</sup>	-	2.0	-	Ω
Forward Transconductance	9fs	V <sub>DS</sub> = 10	00 V, I <sub>D</sub> = 3.6 A <sup>b</sup>	5.4	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	V	<sub>GS</sub> = 0 V,	-	2800	-	pF
Output Capacitance	C <sub>oss</sub>	V	$_{0S} = 25 \text{ V},$	-	250	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0	f = 1.0 MHz, see fig. 5		84	-	
Total Gate Charge	Qg			-	-	190	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 6.1 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13b		-	23	
Gate-Drain Charge	Q <sub>gd</sub>	]	l soo ng. o ana ro	-	-	110	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 500 \text{ V, } I_D = 6.1 \text{ A,}$ $R_g = 6.2 \ \Omega, \ R_D = 81 \ \Omega, \ \text{see fig. } 10^b$		-	19	-	- ns
Rise Time	t <sub>r</sub>			-	35	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	130	-	
Fall Time	t <sub>f</sub>			-	36	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	الم
Internal Source Inductance	L <sub>S</sub>			-	13	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbo	MOSFET symbol showing the		-	6.1	Α
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode		-	-	24	
Body Diode Voltage	$V_{SD}$	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 6.1 A, V <sub>GS</sub> = 0 V <sup>b</sup>		-	-	1.8	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T 25 °C 1 = 4	6.1 A dl/dt = 100 A/vab	-	630	950	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 25  ^{\circ}\text{C}, I_F = 6.1  \text{A, dl/dt} = 100  \text{A/}\mu\text{s}^b$		-	3.5	5.3	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )					L <sub>D</sub> )

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300  $\mu$ s; duty cycle  $\leq$  2 %.



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

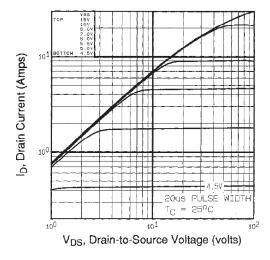


Fig. 1 - Typical Output Characteristics,  $T_C$  = 25 °C

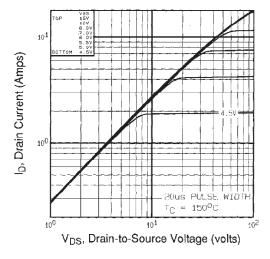
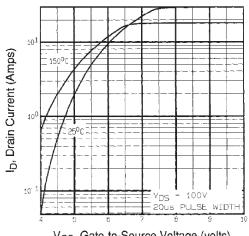


Fig. 2 - Typical Output Characteristics,  $T_C$  = 150 °C



 $V_{GS}$ , Gate-to-Source Voltage (volts)

Fig. 3 - Typical Transfer Characteristics

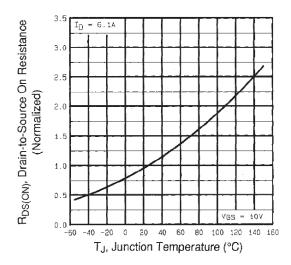


Fig. 4 - Normalized On-Resistance vs. Temperature



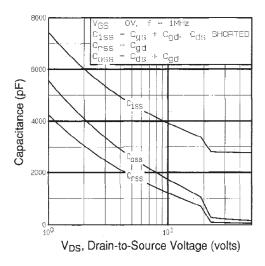


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

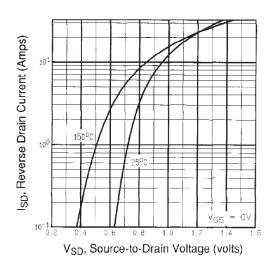


Fig. 7 - Typical Source-Drain Diode Forward Voltage

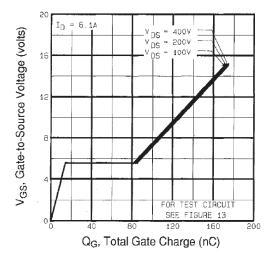


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

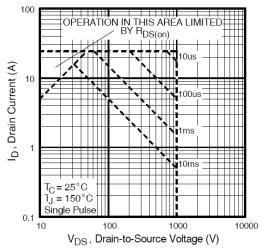


Fig. 8 - Maximum Safe Operating Area



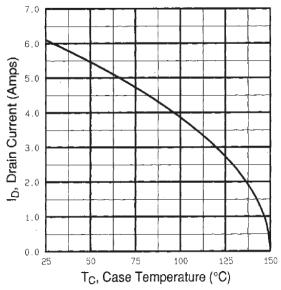


Fig. 9 - Maximum Drain Current vs. Case Temperature

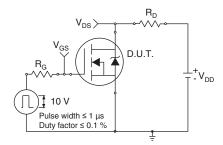


Fig. 10a - Switching Time Test Circuit

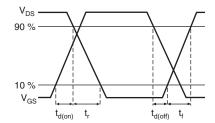


Fig. 10b - Switching Time Waveforms

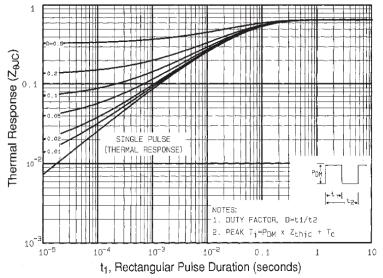
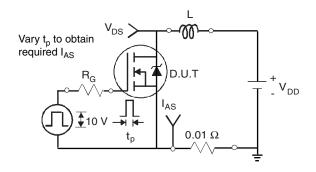


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case





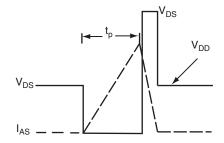


Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

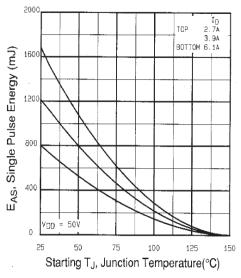


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

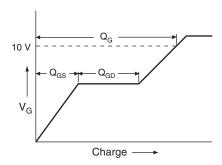


Fig. 13a - Basic Gate Charge Waveform

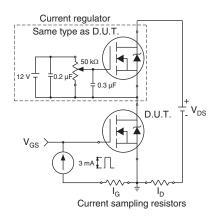
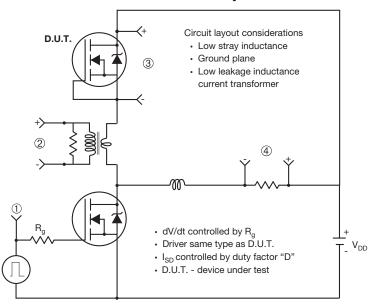


Fig. 13b - Gate Charge Test Circuit



### Peak Diode Recovery dV/dt Test Circuit



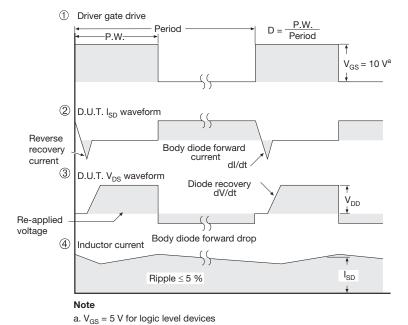
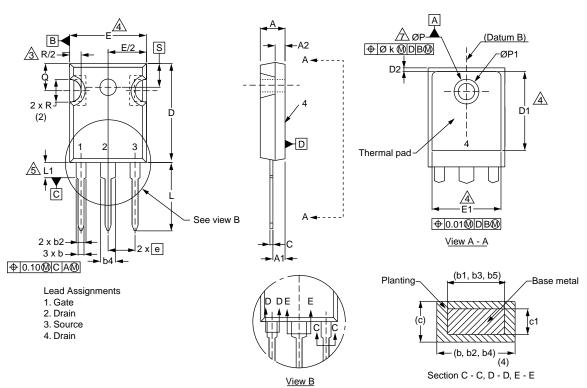


Fig. 14 - For N-Channel



# TO-247AC (High Voltage)



	MILLIM	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.58	5.31	0.180	0.209
A1	2.21	2.59	0.087	0.102
A2	1.17	2.49	0.046	0.098
b	0.99	1.40	0.039	0.055
b1	0.99	1.35	0.039	0.053
b2	1.53	2.39	0.060	0.094
b3	1.65	2.37	0.065	0.093
b4	2.42	3.43	0.095	0.135
b5	2.59	3.38	0.102	0.133
С	0.38	0.86	0.015	0.034
c1	0.38	0.76	0.015	0.030
D	19.71	20.82	0.776	0.820
D1	13.08	-	0.515	-

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D2	0.51	1.30	0.020	0.051
Е	15.29	15.87	0.602	0.625
E1	13.72	ı	0.540	ı
е	5.46	BSC	0.215	BSC
Øk	0.254		0.010	
L	14.20	16.25	0.559	0.640
L1	3.71	4.29	0.146	0.169
Ν	7.62 BSC		0.300 BSC	
ØΡ	3.51	3.66	0.138	0.144
Ø P1	ı	7.39	1	0.291
Q	5.31	5.69	0.209	0.224
R	4.52	5.49	0.178	0.216
S	5.51 BSC		0.217	BSC



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